



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**Brechbuhler Scales, Inc.**

**1424 Scale St. SW  
Canton, OH 44706**

**(and satellite locations as listed on the scope)**

Fulfills the requirements of

**ISO/IEC 17025:2017**

In the field of

**CALIBRATION**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

A handwritten signature in black ink, appearing to read 'R. Douglas Leonard Jr.', is positioned above a horizontal line.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 07 May 2023

Certificate Number: L1051-1



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

## SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

### **Brechbuhler Scales, Inc.**

1424 Scale St. SW  
Canton, OH 44706  
Mike Scott  
330-458-3081

### **Services performed at satellite location**

125 Aries Drive Dundee, MI 48131	3306 Cavalier Drive Fort Wayne, IN 46808
9930 Crescent Park Drive West Chester, OH 45069	5525 Galeao Court Indianapolis, IN 46241
7550 Jacks Lane Clayton, OH 45315	490 S. Mapleton Street Columbus, IN, 47201
520 Old Brookpark Road Cleveland, OH 44109	2351 Jaclyn Court South Bend, IN 46614
4070 Perimeter Drive Columbus, OH 43228	100 McJunkin Road Nitro, WV 25143
1001 Findlay Road Lima, OH 45801	526 31st Street Parkersburg, WV 26101
1080 National Parkway Mansfield, OH 44906	477 North Pike Road Sarver, PA 16055
4005 South Avenue Youngstown, OH 44512	5200 Grand Avenue Pittsburgh, PA 15225

## CALIBRATION

Valid to: **May 7, 2023**

Certificate Number: **L1051-1**

### Mass and Mass Related

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) <sup>2</sup>	Reference Standard, Method and/or Equipment
Class I Weighing Devices <sup>1</sup>	(0 to 100) g	0.3 mg	ASTM E617 Class I Certified Weights
	(100 to 300) g	0.9 mg	
	(300 to 600) g	2.1 mg	
	(600 to 1 000) g	3 mg	
	(1 000 to 2 000) g	6.3 mg	
	(2 000 to 6 000) g	17 mg	
	(6 000 to 12 000) g	36 mg	
Class II Weighing Devices <sup>1</sup>	(0 to 100) g	1.4 mg	ASTM E617 Class II Certified Weights
	(100 to 300) g	13 mg	
	(300 to 600) g	13 mg	
	(600 to 1 000) g	14 mg	
	(1 000 to 2 000) g	130 mg	
	(2 000 to 6 000) g	130 mg	
	(6 000 to 12 000) g	1.3 g	
Class III Weighing Devices <sup>1</sup>	(0 to 1) lb	0.000 61 lb	NIST 105 Class F Certified Weights
	(1 to 5) lb	0.000 92 lb	
	(5 to 50) lb	0.008 8 lb	
	(50 to 500) lb	0.088 lb	
	(500 to 2 500) lb	0.4 lb	
	(2 500 to 5 000) lb	0.88 lb	
	(5 000 to 10 000) lb	1.8 lb	
	(10 000 to 20 000) lb	3.5 lb	
(20 000 to 40 000) lb	8 lb		
Class IIIL Weighing Devices <sup>1</sup>	(0 to 50 000) lb	8.8 lb	NIST 105 Class F Certified Weights
	(50 000 to 200 000) lb	35 lb	
	(200 000 to 400 000) lb	81 lb	

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. Actual uncertainty results may vary from those shown on the Scope depending on the scale or balance with respect to the resolution of the unit, as resolution of the Unit Under Test (UTT) is a major contributing factor to the uncertainty.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. L1051-1.



R. Douglas Leonard Jr., VP, PILR SBU

